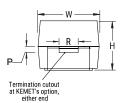


## T493A225K020CH6120

T493 HRA, Tantalum, MnO2 Tantalum, HRA, 2.2 uF, 10%, 20 VDC, SMD, MnO2, Molded, High Reliability, C (0.01%/1000 Hrs), 4 Ohms, 3216, 1.8 mm, 0.8 mm

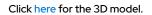
CATHODE (-) END VIEW



ANODE (+) END VIEW

BOTTOM VIEW

SIDE VIEW



General Information	
Series	T493 HRA
Dielectric	MnO2 Tantalum
Style	SMD Chip
Description	SMD, MnO2, Molded, High Reliability
Features	High Reliability
RoHS	No
Prop 65	WARNING: Cancer and reproductive harm - https://www.p65warnings.ca.gov /
SCIP Number	1dd2e1b8-26dd-4d52-927c-6f9 d519011aa
Termination	Tin Lead (SnPb)
AEC-Q200	No
Typical Component Weight	58.97 mg
Notes	P and R dimensions represents the minimum solderable area of the termination surface entirely below cutout (if one is present).

Dimensions	
L	3.2mm +/-0.2mm
W	1.6mm +/-0.2mm
н	1.6mm +/-0.2mm
т	0.13mm REF
S	0.8mm +/-0.3mm
F	1.2mm +/-0.1mm
A	1.2mm MIN
В	0.4mm +/-0.15mm
E	1.3mm REF
G	1.1mm REF
Р	0.35mm MIN
R	0.4mm REF
х	0.1mm +/-0.1mm REF

Specifications	
Capacitance	2.2 uF
Tolerance	10%
Voltage DC	20 VDC (85C), 13.4 VDC (125C)
Temperature Range	-55/+125°C
Rated Temperature	85°C
Dissipation Factor	6% 120Hz 25C
Failure Rate	C (0.01%/1000 Hrs)
ESR	4 Ohms (100kHz 25C)
Ripple Current	137 mA (rms, 100kHz 25C)
Leakage Current	0.5 uA (5min 25°C)
Testing and Reliability	Standard Testing Only

## Packaging SpecificationsPackagingT&R, 178mmPackaging Quantity2000

Statements of suitability for certain applications are based on our knowledge of typical operating conditions for such applications, but are not intended to constitute - and we specifically disclaim - any warranty concerning suitability for a specific customer application or use. This Information is intended for use only by customers who have the requisite experience and capability to determine the correct products for their application. Any technical advice inferred from this Information or otherwise provided by us with reference to the use of our products is given gratis, and we assume no obligation or liability for the advice given or results obtained.